

**STANDARDS**
MALAYSIA

Certificate of Accreditation

No: SAMM 176

Accredited since: 17 September 1999

This is to certify that

SIRIM STANDARDS TECHNOLOGY SDN. BHD.
SENAI, JOHOR
MALAYSIA



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for the current scope of accreditation

has been granted accreditation in respect of the scope of accreditation described in the schedule, subject to the terms and conditions governing the *Skim Akreditasi Makmal Malaysia* (SAMM), the Laboratory Accreditation Scheme of Malaysia.

Laboratories accredited under SAMM meet the requirements of MS ISO/IEC 17025. This Malaysian Standard is identical with ISO/IEC 17025 published by the International Organization for Standardization (ISO).



(DATUK FADILAH BAHARIN)
Director General
Department of Standards Malaysia

Date of issue: 6 December 2017

NO: SAMM 176

Page: 1 of 27

LABORATORY LOCATION:
(PERMANENT LABORATORY)

SIRIM STANDARDS TECHNOLOGY SDN. BHD.
BANGUNAN SIRIM BERHAD
NO. 3, JALAN TEKNOLOGI 5
TAMAN TEKNOLOGI JOHOR
81400 SENAI, JOHOR
MALAYSIA

FIELDS OF CALIBRATION:

ELECTRICAL, DIMENSIONAL, TEMPERATURE,
MASS, FORCE AND PRESSURE

This laboratory has demonstrated its technical competence to operate in accordance with MS ISO/IEC 17025:2005 (ISO/IEC 17025:2005).

This laboratory's fulfillment of the requirements of ISO/IEC 17025 means the laboratory meets both the technical competence requirements and management system requirements that are necessary for it to consistently deliver technically valid test results and calibrations. The management system requirements in ISO/IEC 17025 are written in language relevant to laboratory operations and operate generally in accordance with the principles of ISO 9001 (see Joint ISO-ILAC-IAF Communiqué dated April 2017).

* The expanded uncertainties are based on an estimated confidence probability of approximately 95% and have a coverage factor of $k=2$ unless stated otherwise.

SCOPE OF CALIBRATION: ELECTRICAL

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
1. Measuring Instruments			
(a) DC Voltage	0 mV to 330 mV 330 mV to 3.3 V 3.3V to 33 V 33 V to 330 V 330 V to 1020 V	1.6 μ V 3.2 μ V 20 μ V 180 μ V 1.7 mV	Generation using calibrator model Fluke 5522 A
(b) Resistance	0 Ω to 11 Ω 11 Ω to 33 Ω 33 Ω to 110 Ω 110 Ω to 330 Ω 330 Ω to 1.1k Ω 1.1 k Ω to 3.3 k Ω 3.3 k Ω to 11 k Ω 11 k Ω to 33 k Ω 33 k Ω to 110 k Ω 110 k Ω to 330 k Ω 330 k Ω to 1.1 M Ω 1.1 M Ω to 3.3 M Ω 3.3 M Ω to 11 M Ω 11 M Ω to 33 M Ω 33 M Ω to 100 M Ω 100 M Ω to 330 M Ω 330 M Ω to 1100 M Ω	220 μ Ω 200 μ Ω 740 μ Ω 1.3 m Ω 4.3 m Ω 12 m Ω 54 m Ω 160 m Ω 450 m Ω 1.7 Ω 9 Ω 34 Ω 140 Ω 1.1 k Ω 2.7 k Ω 79 k Ω 560 k Ω	Generation using calibrator model Fluke 5522 A

NO: SAMM 176

Page: 2 of 27

SCOPE OF CALIBRATION: ELECTRICAL

Instrument Calibrated / Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
1. Measuring Instruments (continued) (b) Resistance	0 Ω to 1 Ω 1 Ω to 100 Ω 100 Ω to 10 k Ω 10 k Ω to 100 k Ω 10 k Ω to 10 M Ω	6 $\mu\Omega$ 1 m Ω 1 m Ω 700 m Ω 22 Ω	Generation using Decade resistance box Yokogawa 2793 & Standard Resistor Yokogawa 2792
(c) DC Current	0 μ A to 330 μ A 330 mA to 3.3 mA 3.3 mA to 33 mA 33 mA to 330 mA 330 mA to 1.1 mA 1.1 A to 3 A 3 A to 10 A 10 A to 21 A	5.2 nA 34 nA 910 nA 8.7 μ A 42 μ A 100 μ A 1.4 mA 9 mA	Generation using calibrator model Fluke 5522 A
(d) AC Voltage (See Matrix A)	See Matrix A	See Matrix A	Generation using calibrator model Fluke 5522 A

Matrix A
AC Voltage Measurement

Range	Frequency									
	10 Hz to 45 Hz	45 Hz to 1 kHz	1 kHz to 5 kHz	5 kHz to 10 kHz	1 kHz to 10 kHz	45 Hz to 10 kHz	10 kHz to 20 kHz	20 kHz to 50 kHz	50 kHz to 100 kHz	100 kHz to 500 kHz
0 to 33 mV	2 μ V	-	-	-	-	2.4 μ V	2 μ V	3.0 μ V	5.0 μ V	26 μ V
33 mV to 330 mV	13 μ V	-	-	-	-	7.3 μ V	8 μ V	9.5 μ V	12 μ V	20 μ V
330 mV to 3.3 V	73 μ V	-	-	-	-	59 μ V	71 μ V	100 μ V	140 μ V	3 mV
3.3 V to 33 V	810 μ V	-	-	-	-	710 μ V	810 μ V	1.8 mV	2.8 mV	-
33 V to 330 V	-	9.9 mV	-	-	8.2 mV	-	10 mV	22 mV	74 mV	-
330 V to 1020 V	-	33 mV	35 mV	37 mV	-	-	-	-	-	-

SCOPE OF CALIBRATION: ELECTRICAL

Instrument Calibrated / Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
1. Measuring Instruments (continued)			
(e) AC Current (See Matrix B)	See Matrix B	See Matrix B	Generation using calibrator model Fluke 5522 A
(f) Frequency Measure (Measuring Instrument)	DC 0 MHz to 60 MHz 60 MHz to 2 GHz	5 Hz 1 Hz	Generate using Function Generator HP 3325 B / Signal Generator Agilent E4420B
(g) Level	+ 7 dBm to -70 dBm	1.5 dBm	
(h) Capacitance	1 μ F to 3.3 μ F 3.3 μ F to 11 μ F 11 μ F to 33 μ F 33 μ F to 110 μ F 110 μ F to 330 μ F 0.33 mF to 1.1 mF 1.1 mF to 3.3 mF 3.3 mF to 11 mF 11 mF to 33 mF 33 mF to 110 mF	9.3 nF 21 nF 85 nF 290 nF 920 nF 6.4 μ F 19 μ F 37 μ F 130 μ F 540 μ F	Generate using Fluke 5522A

Matrix B
AC Current Measurement

Range	Frequency								
	10 Hz to 20 Hz	10 Hz to 45 Hz	20 Hz to 45 Hz	45 Hz to 100 Hz	45 Hz to 1 kHz	100 Hz to 1 kHz	1 kHz to 5 kHz	5 kHz to 10 kHz	10 kHz to 30 kHz
0 to 330 μ A	28 nA	-	26 nA	-	26 nA	-	33 nA	72 nA	340 nA
0.33 mA to 3.3 mA	630 nA	-	620 nA	-	620 nA	-	630 nA	650 nA	920 nA
3.3 mA to 33 mA	4.9 μ A	-	3.4 μ A	-	5.7 μ A	-	9.9 μ A	10 μ A	13 μ A
33 mA to 330 mA	46 μ A	-	28 μ A	-	27 μ A	-	31 μ A	36 μ A	50 μ A
330 mA to 1.1 A	-	590 μ A	-	-	160 μ A	-	200 μ A	380 μ A	-
1.1 A to 3 A	-	330 μ A	-	-	440 μ A	-	930 μ A	2 mA	-
3 A to 10 A	-	-	-	1 mA	-	1 mA	4.5 mA	-	-
10 A to 21 A				6 mA		6 mA	11 mA		
20 A to 50 A				300 mA					

NO: SAMM 176

Page: 4 of 27

SCOPE OF CALIBRATION: ELECTRICAL

Instrument Calibrated / Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
2. Insulation Tester (Max. Voltage 1000 V)	10 k Ω to 100 k Ω 100 k Ω to 10 M Ω 10 M Ω to 100 M Ω 100 M Ω to 1000 M Ω 1000 M Ω to 10 G Ω	0.58 Ω 580 Ω 6 k Ω 69 k Ω 600 k Ω	Generate using high resistance decade box IET HRRS
3. Sourcing/Generating Instrument (a) DC Voltage	0 mV to 100 mV 100 mV to 10 V 10 V to 100 V 100 V to 1000 V	1.6 μ V 59 μ V 1.2 mV 13 mV	Measure using System Multimeter HP 3458A
(b) DC Current	0 μ A to 10 mA 10 mA to 100 mA 100 mA to 1 A	580 nA 7.8 μ A 590 μ A	Measure using System Multimeter HP 3458A
(c) AC Voltage	100 mV to 10 V 40 Hz to 20 kHz 50 kHz to 1 MHz 10 V to 100 V 40 Hz to 1 kHz 100 V to 700 V 40 Hz to 1 kHz	590 μ V 604 μ V 6 mV 59 mV	Measure using System Multimeter HP 3458A
(d) AC Current At 1 kHz	0 to 10 mA 10 mA to 100 mA 100 mA to 1 A	71 μ A 23 μ A 780 μ A	Measure using System Multimeter HP 3458A
(e) Resistance	0 Ω to 10 Ω 10 Ω to 100 Ω 100 Ω to 1 k Ω 1 k Ω to 10 k Ω 10 k Ω to 100 k Ω 100 k Ω to 1 M Ω 1 M Ω to 10 M Ω	665 μ Ω 6 m Ω 16 m Ω 150 m Ω 1.7 Ω 24 Ω 730 Ω	Measure using System Multimeter HP 3458A

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NO: SAMM 176

Page: 5 of 27

SCOPE OF CALIBRATION: ELECTRICAL

Instrument Calibrated / Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
(e) Resistance (continued)	0 Ω to 10 Ω	230 $\mu\Omega$	Measure using System Multimeter HP 3458A
	10 Ω to 100 Ω	1.9 m Ω	
	100 Ω to 1 k Ω	15 m Ω	
	1 k Ω to 10 k Ω	125 m Ω	Measure (direct measurement for resistance boxes)
	10 k Ω to 100 k Ω	620 m Ω	
	100 k Ω to 1 M Ω	19 Ω	
	1 M Ω to 10 M Ω	230 Ω	
	10 M Ω to 100 M Ω	13 k Ω	Measure using System Multimeter HP 3458A Measure (Standard Resistors)
	0 Ω to 1 Ω	79 $\mu\Omega$	
	1 Ω to 10 Ω	230 $\mu\Omega$	
i) DC Current:	1 A to 2 A	210 μ A	Measure using System Multimeter HP 3458 A & AC / DC Current Shunt Ballantine 1625 A
	2 A to 10 A	3 mA	
	ii) AC Current to 1 kHz:	0 A to 2 A	
		2 A to 10 A	
	iii) AC Current 1 to 5 kHz:	0 A to 10 A	
		22 mA	
	iv) AC Current 5 to 10 kHz:	0 A to 2 A	
		1 mA	
	DC Current (Source)	10 A to 20 A	
		20 A to 100 A	
AC Current @ 50 Hz to 1 kHz (Source)	0 A to 20 A	21 mA	
	0 A to 100 A	40 mA	
	(f) Frequency	3 GHz to 5 GHz	
		0 MHz to 3 GHz	

NO: SAMM 176

Page: 6 of 27

SCOPE OF CALIBRATION: ELECTRICAL

Instrument Calibrated / Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
4. High Voltage Meters/ Testers	DC V : 0 - 40 kV AC V : 0 - 28 kV (peak ac at 50 Hz)	31 V 120 V	Measure with probes using Digital Multimeter & High Voltage Probe Fluke 80K-40
	DC V : 0 - 2 kV DCV : 2 – 20 kV AC V : 0 - 2 kV at 50 Hz	600 mV 1.0 V 700 mV	Measure direct using Precision High Voltage Meter Vitrek 4700
	AC V : 2 - 20 kV at 50 Hz	17 V	
	DC V : 0 - 10 kV AC V : 0 - 10 kV at 50 Hz	1.0 V 17 V	Generate using Withstanding Voltage Tester Kikusui TOS 5101 & Precision High Voltage Meter Vitrek 4700
5. Clamp Meters	DC Current 0 A to $\pm$ 10 A (up to 1000 A via multi-turn coil – 10 & 50 Turn Coil)	57 mA	Generate using Calibrator Wavetek 9100
	AC Current 0 A to $\pm$ 10 A 40 Hz to 440 Hz (up to 1000 A via multi-turn coil – 10 & 50 Turn Coil)	61 mA	
	AC Current 10 A to 20 A 40 Hz to 110 Hz	73 mA	

Scan this QR Code or visit www.ism.gov.my/cab-directories for the current scope of accreditation

NO: SAMM 176

Page: 7 of 27

SCOPE OF CALIBRATION: ELECTRICAL

Instrument Calibrated / Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
6. Withstanding / Insulation Voltage Testers			
(a) Generate: (direct)	DC V: 0 kV to 20 kV AC V: 0 kV to 20 kV at 50 Hz	1.2 V 17 V	Measure using Precision High Voltage Meter Vitrek 4700
(b) Resistance (Measure)	10 k Ω to 100 k Ω 100 k Ω to 10 M Ω 10 M Ω to 100 M Ω 100 M Ω to 1000 M Ω 1000 M Ω to 10 G Ω	0.58 Ω 577 Ω 6 k Ω 69 k Ω 600 k Ω	Generate using high resistance decade box IET HRRS
(c) Cut Off Current (AC Current)	0 mA to 1.0 mA 1.0 mA to 2.0 mA 2.0 mA to 5.0 mA 5.0 mA to 10.0 mA	12 μ A 31 μ A 60 μ A 110 μ A	Measure using Cut Off Current Kikusui TLC 501 B
(d) Timing	0 sec to 60 sec 1 min to 15 min 15 min to 25 min	62 msec 85 msec 800 msec	Measure using Time Calibrator SST-2

Note : dBm is measured relative to 1 mW

NO: SAMM 176

Page: 8 of 27

SCOPE OF CALIBRATION: ELECTRICAL

Instrument Calibrated / Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
7. Oscilloscope			
(a) Amplitude	100 V	51 mV	Generate using Calibration Generator Tektronix PG 506A
	50 V	51 mV	
	20 V	170 μ V	
	10 V	45 μ V	
	5 V	23 μ V	
	2 V	9.4 μ V	
	1 V	4.8 μ V	
	0.5 V	2.5 μ V	
	0.2 V	1.2 μ V	
	0.1 V	900 nV	
	10 mV	900 nV	
	1 mV	900 nV	
(b) Sweep	0.1 μ s	570 ps	Generate using Time Mark Generator Tektronix TG 501A
	0.2 μ s	1.2 ns	
	0.5 μ s	2.8 ns	
	1 μ s	4 ns	
	2 μ s	9 ns	
	5 μ s	22 ns	
	10 μ s to 0.1 ms	460 ns	
	0.2 ms	820 ns	
	0.5 ms	2 μ s	
	1 ms	4.5 μ s	
	2 ms	8 μ s	
	5 ms	20 μ s	
	10 ms	45 μ s	
	20 ms	80 μ s	
	50 ms	200 μ s	
	0.1 s	460 μ s	
	0.2 s	930 μ s	
	0.5 s	2 ms	
	1 s to 2 s	4.5 ms	
	5 s	23 ms	
(c) Bandwidth	0.25 MHz to 250 MHz	23 kHz	Generate using Levelled Sine Wave Generator Tegam SG 503
	250 MHz to 1 GHz	230 kHz	
			Generate using Signal Generator Agilent E 4420 B

NO: SAMM 176

Page: 9 of 27

SCOPE OF CALIBRATION: ELECTRICAL

Instrument Calibrated / Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
8. LCR Meters. Measuring Instruments. i) Inductance:	Frequency Range: 100 Hz to 1 kHz 100 μ H to 1000 μ H 1 mH to 10 mH 10 mH to 100 mH 100 mH to 1000 mH 1 H to 10 H	110 nH 800 nH 12 μ H 82 μ H 790 μ H	Generate using Decade Inductor GR 1491G
ii) Capacitance:	Frequency Range: 100 Hz to 1 kHz 1 pF to 100 pF 100 pF to 10000 pF 10 nF to 100 nF 100 nF to 1000 nF	0.084 pF 0.57 pF 12 pF 570 pF	Generate using Decade Capacitor GR 1413
9. Time	0 sec to 10 sec 0 sec to 100 sec 0 sec to 1000 sec 0 sec to 10000 sec 0 min to 100 min 0 hr to 24 hr	120 msec 120 msec 130 msec 590 msec 590 msec 590 msec	Measure using Time Calibrator SST-2
10. RPM Related Measuring Instruments (Non Contact Type)	60 rpm to 5999 rpm 6000 rpm to 29999 rpm 30000 rpm to 59999 rpm 60000 rpm to 99999 rpm	0.07 rpm 7 rpm 36 rpm 120 rpm	In-House Method ESF/0303
11. Power Meters/ Indicating Instruments a) DC Power	0.1 W to 1 kW 1 kW to 20 kW	$0.26 \frac{mW}{W} + 0.46 mW$ $0.93 \frac{mW}{W} - 120 mW$	Generate using Fluke 5522A
b) AC Power 45 Hz to 65 Hz at PF = 1	0.1 W to 1 W 1 W to 10 kW 10 kW to 20 kW	$0.59 \frac{mW}{W} + 0.47 mW$ $1.1 \frac{mW}{W} + 430 mW$ $1.2 \frac{mW}{W} + 580 mW$	Generate using Fluke 5522A

Signatory:

1. Gurdeep Singh a/l Gurdial Singh

NO: SAMM 176

Page: 10 of 27

SCOPE OF CALIBRATION: ELECTRICAL**SITE: CATEGORY I**

Instrument calibrated/ Measurement parameter	Range	Calibration and Measurement Capability expressed as an uncertainty($\pm$)*	Remarks
1. Measuring Instruments (a) DC Voltage	0 mV to 330 mV 330 mV to 3.3 V 3.3 V to 33 V 33 V to 330 V 330 V to 1020 V	1.4 μ V 15 μ V 160 μ V 880 μ V 8.6 mV	Generation using calibrator model Fluke 5522 A
(b) AC Voltage	See Matrix C See Matrix D	See Matrix C See Matrix D	Generation using calibrator model Fluke 5522 A & Wavetek 9100

Matrix C
AC Voltage Measurement

Range	Frequency									
	10 Hz to 45 Hz	45 Hz to 1 kHz	1 kHz to 5 kHz	5 kHz to 10 kHz	45 Hz to 10 kHz	1 kHz to 10 kHz	10 kHz to 20 kHz	20 kHz to 50 kHz	50 kHz to 100 kHz	100 kHz to 500 kHz
0 mV to 33 mV	8 μ V	-	-	-	7.1 μ V	-	7.2 μ V	8.1 μ V	18 μ V	67 μ V
33 mV to 330 mV	9.6 μ V	-	-	-	9.4 μ V	-	9 μ V	9.6 μ V	38 μ V	83 μ V
330 mV to 3.3 V	400 μ V	-	-	-	240 μ V	-	290 μ V	400 μ V	950 μ V	3.5 mV
3.3 V to 33 V	1.9 mV	-	-	-	1.3 mV	-	1.6 mV	2.0 mV	5.3 mV	-
33 V to 330 V	-	9.6 mV	-	-	-	15 mV	17 mV	18 mV	130 mV	-
330 V to 1020 V	-	130 mV	110 mV	130 mV	-	-	-	-	-	-

NO: SAMM 176

Page: 11 of 27

SCOPE OF CALIBRATION: ELECTRICAL

SITE: CATEGORY I

Instrument calibrated/ Measurement parameter	Range	Calibration and Measurement Capability expressed as an uncertainty($\pm$)*	Remarks
(c) DC Current	0 to 330 μ A 330 μ A to 3.3 mA 3.3 mA to 33 mA 33 mA to 330 mA 330 mA to 1.1 A 1.1 A to 3 A 3 A to 11 A 11 A to 21 A	25 nA 170 nA 670 nA 6.7 μ A 280 μ A 530 μ A 2.4 mA 15 mA	Generation using calibrator model Fluke 5522 A
(d) AC Current	See Matrix E See Matrix F	See Matrix E See Matrix F	Generation using calibrator model Fluke 5522 A & Wavetek 9100

Matrix D
AC Voltage Measurement

Range	Frequency									
	10 Hz to 45 Hz	45 Hz to 1 kHz	1 kHz to 5 kHz	5 kHz to 10 kHz	45 Hz to 10 kHz	1 kHz to 10 kHz	10 kHz to 20 kHz	20 kHz to 50 kHz	50 kHz to 100 kHz	100 kHz to 500 kHz
800 V to 1000 V	-	-	-	-	-	-	1.7 V	-	-	-

Matrix E
AC Current Measurement

Range	Frequency								
	10 Hz to 20 Hz	10 Hz to 45 Hz	20 Hz to 45 Hz	45 Hz to 100 Hz	100 Hz to 1 kHz	45 Hz to 1 kHz	1 kHz to 5 kHz	5 kHz to 10 kHz	10 kHz to 30 kHz
0 μ A to 330 μ A	120 nA	-	120 nA	-	-	120 nA	180 nA	240 nA	480 nA
0.33 mA to 3.3 mA	2.6 μ A	-	1.7 μ A	-	-	1.5 μ A	2.6 μ A	6.2 μ A	12 μ A
3.3 mA to 33 mA	4.4 μ A	-	3.4 μ A	-	-	7.0 μ A	12 μ A	27 μ A	51 μ A
33 mA to 330 mA	85 μ A	-	54 μ A	-	-	37 μ A	92 μ A	190 μ A	370 μ A
330 mA to 1.1 A	-	2.2 mA	-	-	-	0.3 mA	8.1 mA	350 mA	-
1.1 A to 3 A	-	2.2 mA	-	-	-	0.81 mA	8.1 mA	35 mA	-
3 A to 11 A	-	-	-	4.4 mA	5.8 mA	-	110 mA	-	-
11 A to 20.5 A	-	-	-	21 mA	24 mA	-	350 mA	-	-

NO: SAMM 176

Page: 12 of 27

SCOPE OF CALIBRATION: ELECTRICAL**SITE: CATEGORY I**

Matrix F

AC Current Measurement

Range	Frequency								
	10 Hz to 20 Hz	10 Hz to 45 Hz	20 Hz to 45 Hz	45 Hz to 100 Hz	100 Hz to 1 kHz	45 Hz to 1 kHz	1 kHz to 5 kHz	5 kHz to 10 kHz	10 kHz to 30 kHz
11 A to 20 A	-	-	-	-	-	-	-	160 mA	-

Instrument calibrated/ Measurement parameter	Range	Calibration and Measurement Capability expressed as an uncertainty($\pm$)*	Remarks
(e) Resistance	0 to 11 Ω	1.2 m Ω	Generation using calibrator model Fluke 5522 A
	11 Ω to 33 Ω	2.1 m Ω	
	33 Ω to 110 Ω	2.7 m Ω	
	110 Ω to 330 Ω	5.9 m Ω	
	330 Ω to 1.1 k Ω	35 m Ω	
	1.1 k Ω to 3.3 k Ω	62 m Ω	
	3.3 k Ω to 11 k Ω	130 m Ω	
	11 k Ω to 33 k Ω	620 m Ω	
	33 k Ω to 110 k Ω	1.3 Ω	
	110 k Ω to 330 k Ω	6.4 Ω	
	330 k Ω to 1.1 M Ω	39 Ω	
	1.1 M Ω to 3.3 M Ω	120 Ω	
	3.3 M Ω to 11 M Ω	570 Ω	
	11 M Ω to 33 M Ω	6.4 k Ω	
	33 M Ω to 110 M Ω	23 k Ω	
	110 M Ω to 330 M Ω	500 k Ω	
	330 M Ω to 1100 M Ω	6.3 M Ω	
Resistance Up to 1000 Vmax	100 Ω to 1 k Ω	140 m Ω	Generate using High Resistance Decade Substitute IET HRRS & Yokogawa 2793
	1 k Ω to 10 k Ω	57 Ω	
	10 k Ω to 100 k Ω	58 Ω	
	100 k Ω to 1000 k Ω	130 Ω	
	1000 k Ω to 10 M Ω	1.5 k Ω	
	10 M Ω to 100 M Ω	24 k Ω	
	100 M Ω to 1000 M Ω	270 k Ω	
	1000 M Ω to 10 G Ω	130 M Ω	
	0 Ω to 1 Ω	6 $\mu\Omega$	
	1 Ω to 100 Ω	1 m Ω	
			ESD/0360 Rev 5.0 Generating using Standard Resistor & Decade Resistance Box model Yokogawa 2792 & 2793 respectively

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NO: SAMM 176

Page: 13 of 27

SCOPE OF CALIBRATION: ELECTRICAL**SITE: CATEGORY I**

Instrument calibrated/ Measurement parameter	Range	Calibration and Measurement Capability expressed as an uncertainty($\pm$)*	Remarks
(f) Frequency	0.01 Hz to 120 Hz 120 Hz to 1200 Hz 1.2 kHz to 12 kHz 12 kHz to 120 kHz 120 kHz to 1200 kHz 1.2 MHz to 3.2 MHz 3.2 MHz to 10 MHz	9.0 μ Hz 9.0 mHz 29 mHz 290 mHz 820 mHz 110 Hz 350 kHz	Generation using calibrator model Fluke 5522 A
(g) Capacitance	220 pF to 400 pF 0.4 nF to 1.1 nF 1.1 nF to 3.3 nF 3.3 nF to 11 nF 11 nF to 33 nF 33 nF to 110 nF 110 nF to 330 nF 0.33 μ F to 1.1 μ F 1.1 μ F to 3.3 μ F 3.3 μ F to 11 μ F 11 μ F to 33 μ F 33 μ F to 110 μ F 110 μ F to 330 μ F 0.33 mF to 1.1 mF 1.1 mF to 3.3 mF 3.3 mF to 11 mF 11 mF to 33 mF 33 mF to 110 mF	13 pF 17 pF 23 pF 40 pF 98 pF 300 pF 900 pF 4.1 nF 9.3 nF 21 nF 85 nF 290 nF 920 nF 6.4 μ F 19 μ F 38 μ F 130 μ F 540 μ F	Generation using calibrator model Fluke 5522 A
Frequency range 100 Hz to 1 KHz	1 pF to 100 pF 100 pF to 10000 pF 10 nF to 100 nF 100 nF to 1000 nF	0.67 pF 1 pF 12 pF 570 pF	ESD/0360 Rev 5.0 Generation using Decade Capacitor model GR 1413
(h) Inductance	100 μ H to 1000 μ H 1 mH to 10 mH 10 mH to 100 mH 100 mH to 1000 mH 1 H to 10 H	0.16 μ H 0.28 mH 0.34 mH 0.95 mH 0.3 H	ESD/0360 Rev 5.0 Generating using Decade Inductor model GR 1491-G

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NO: SAMM 176

Page: 14 of 27

SCOPE OF CALIBRATION: ELECTRICAL

SITE: CATEGORY I

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
2. Source / Generating Instruments	(a) DC Voltage	0 mV to 100 mV	Measured using Multimeter HP 3458A
	100 mV to 1 V	2.2 μ V	
	1 V to 10 V	14 μ V	
	10 V to 100 V	230 μ V	
	100 V to 1000 V	1.5 mV	
	(b) DC Current	0 mA to 10 mA	Measured using Multimeter HP 3458A & Active Shunt Ballantine 1625A
	10 mA to 100 mA	9.1 μ A	
	100 mA to 1000 mA	72 μ A	
	1 A to 3 A	1.6 mA	
	3 A to 20 A	5.7 mA	
	(c) AC Voltage	0 mV to 10 mV (40 Hz to 1 kHz)	Measured using Multimeter HP 3458A
	100 mV to 10 V (40 Hz to 1 kHz)	20 mA	
	10 V to 100 V (40 Hz to 1 kHz)	5.4 μ V	
	100 V to 1000 V (40 Hz to 1 kHz)	1.2 mV	
	(d) AC Current	0 A to 1 A (10 Hz to 5 kHz)	Measured using Multimeter HP 3458A & Active Shunt Ballantine 1625A
	1 A to 3 A (10 Hz to 5 kHz)	2.3 mA	
	3 A to 20 A (10 Hz to 1 kHz)	8.1 mA	
	20 A to 100 A (10 Hz to 1 kHz)	26 mA	
		130 mA	

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NO: SAMM 176

Page: 15 of 27

SCOPE OF CALIBRATION: ELECTRICAL

SITE: CATEGORY I

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
3. High Voltage Measurement - High Voltage Testers / Puncture Testers / Spark Testers			
DC Voltage	0 kV to 2 kV 2 kV to 5 kV 5 kV to 10 kV 10 kV to 15 kV 15 kV to 20 kV	1.3 V 7.9 V 11 V 13 V 16 V	Measured using High Voltage Meter Vitrek 4700A
AC Voltage 20 Hz to 100 Hz	0 kV to 2 kV 2 kV to 5 kV 5 kV to 10 kV 10 kV to 15 kV 15 kV to 20 kV	4 V 30 V 34 V 45 V 57 V	
Cut Off Current AC Current 40 Hz to 1 kHz	0 mA to 0.5 mA 0.5 mA to 1 mA 1 mA to 2 mA 2 mA to 5 mA 5 mA to 10 mA	0.03 mA 0.05 mA 0.06 mA 0.12 mA 0.20 mA	Measured using cut-off current meter TLC-501B
4. Timer	0 sec to 10 sec 0 sec to 100 sec 0 sec to 1000 sec 0 sec to 10000 sec 0 min to 100 min 0 hr to 24 hr	120 msec 120 msec 130 msec 570 msec 570 msec 570 msec	Measure using Time Calibrator SST-2
5. Source Instruments Resistance	0 to 10 Ω 10 Ω to 100 Ω 100 Ω to 1 k Ω 1 k Ω to 10 k Ω 10 k Ω to 100 k Ω 100 k Ω to 1 M Ω 1 M Ω to 10 M Ω 10 M Ω to 100 M Ω 100 M Ω to 1 G Ω	240 $\mu\Omega$ 2 m Ω 2.9 m Ω 130 m Ω 180 m Ω 20 Ω 690 Ω 59 k Ω 590 k Ω	Measure using Multimeter HP 3458 A

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NO: SAMM 176

Page: 16 of 27

SCOPE OF CALIBRATION: ELECTRICAL**SITE: CATEGORY I**

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
6. Oscilloscope (a) Vertical Deflection (Square Wave Signal)	100 V 50 V 20 V 10 V 5 V 2 V 1 V 0.5 V 0.2 V 0.1 V 10 mV 1 mV	51 mV 51 mV 170 μ V 45 μ V 23 μ V 9.4 μ V 4.8 μ V 2.5 μ V 1.2 μ V 900 nV 900 nV 5.2 μ V	Generate using Calibration Generator Tektronix PG 506A
(b) Vertical Deflection (DC Signal)	0mV to 330 mV 330 mV to 3.3 V 3.3 V to 33 V 33 V to 330 V 330 V to 1020 V	1.6 μ V 23 μ V 24 μ V 290 μ V 3.3 mV	Generation using Calibrator model Fluke 5522 A
(C) Sweep	0.1 μ s 0.2 μ s 0.5 μ s 1 μ s 2 μ s 5 μ s 10 μ s to 0.1 ms 0.2 ms 0.5 ms 1 ms 2 ms 5 ms 10 ms 20 ms 50 ms 0.1 s 0.2 s 0.5 s 1 s to 2 s 5 s	570 ps 1.2 ns 2.8 ns 4 ns 9 ns 22 ns 460 ns 820 ns 2 μ s 4.6 μ s 8 μ s 20 μ s 45 μ s 80 μ s 200 μ s 460 μ s 930 μ s 2 ms 4.6 ms 23 ms	Generate using Time Mark Generator Tektronix TG 501Ajim
(d) Bandwidth	0.25 MHz to 250 MHz 250 MHz to 4 GHz	23 kHz 230 kHz	Generate using Levelled Sine Wave Generator Tegam SG 503 & Signal Generator Agilent E4433B

NO: SAMM 176

Page: 17 of 27

SCOPE OF CALIBRATION: ELECTRICAL

SITE: CATEGORY I

Instrument Calibrated / Measurement Parameter	Range	Calibration and measurement capability expressed as an Uncertainty ($\pm$) *	Remarks
7. Sourcing / Generating Instrument			
(a) Frequency	0 Hz to 5 GHz	215 nHz	Measure using Universal Counter Agilent 53132A Measure using Spectrum Analyzer Agilent E4445A
	5 GHz to 13 GHz	0.1 μ Hz	
(b) Amplitude / Level	-150 dB to +30 dB (3 Hz to 13 GHz)	1 dBm	Measure using Spectrum Analyzer Agilent E4445A
8. Measuring Instrument			
	0 MHz to 60 MHz	5 Hz	Generate using Synthesizer Function Generator HP 3325 B
(a) Frequency	60 MHz to 4 GHz	1 Hz	Generate using Signal Generator Agilent E4433B
(b) Amplitude / Level	+ 20 dBm to -136 dBm	0.9 dBm	Generate using Signal Generator Agilent E4433B
9. Power Meters/ Indicating Instruments			
a) DC Power	0.1 W to 1 kW	$0.26 \frac{mW}{W} + 0.46 mW$	Generate using Fluke 5522A
	1 kW to 20 kW	$0.93 \frac{mW}{W} - 120 mW$	
b) AC Power	0.1 W to 1 W	$0.59 \frac{mW}{W} + 0.47 mW$	Generate using Fluke 5522A
45 Hz to 65 Hz at PF = 1	1 W to 10 kW	$1.10 \frac{mW}{W} + 430 mW$	
	10 kW to 20 kW	$1.20 \frac{mW}{W} + 580 mW$	

Signatory:

1. Gurdeep Singh a/l Gurdial Singh

Schedule

Issue date: 6 December 2017
Valid until: 17 September 2020



MS ISO/IEC 17025

NO: SAMM 176

Page: 18 of 27

SCOPE OF CALIBRATION: DIMENSIONAL

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
1. Micrometer	Up to 25 mm travers 25 mm to 50 mm 50 mm to 75 mm 75 mm to 100 mm	1 μ m 1 μ m 2 μ m 2 μ m	Calibrated using Steel Gauge Block as a Standard with reference to ISO 3611: 2010
2. Caliper	Up to 200 mm 200 mm to 600 mm	6 μ m 11 μ m	Calibrate using Caliper Checker as a Standard with reference to JIS B 7507:1993
3. Caliper Checker (Outside measurement only)	20 mm to 350 mm 350 mm to 450 mm	3 μ m 5 μ m	Calibrate using Steel Gauge Block set as a Standard & Linear Height Gauge as a comparator
4. Standard Rod	20 mm to 150 mm 150 mm to 300 mm	3 μ m 4 μ m	Calibrate using Steel Gauge Block set as a Standard & Linear Height Gauge as a comparator
5. Calibration Tester	0.001 mm to 25 mm	0.8 μ m	Calibrate using Steel Gauge Block set as a Standard & Sylvac as a Standard
6. Dial Thickness Gauge	0.001 mm to 50 mm 50 mm to 100 mm	1 μ m 2 μ m	Calibrate using Gauge Steel Block set as a Standard
7. Pin Gauge (Diameter Only)	0.2 mm to 40 mm	3.1 μ m	Using Std. Pin Gauge set as a Standard & Laser Micrometer as a comparator
8. Feeler Gauge	0.005 mm to 2 mm	1.0 μ m	Calibrate using Steel Gauge Block set as a Standard & Sylvac Probe as a comparator with reference to JIS-B-7524: 2008 (clause 5:1)

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Schedule

Issue date: 6 December 2017
Valid until: 17 September 2020



MS ISO/IEC 17025

NO: SAMM 176

Page: 19 of 27

SCOPE OF CALIBRATION: DIMENSIONAL

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
9. Dial Test Indicator	0.01 mm to 1 mm	3 μ m	Calibrate using Calibration Tester as a Standard with reference to JIS-B-7533:1990
10. Dial Gauge	0.01 mm to 100 mm	4 μ m	Calibrate using Calibration Tester as a Standard with reference to JIS-B-7503:1997
11. Depth Gauges / Micrometer	0.001 to 300 mm	7 μ m	Calibrate using Depth Microchecker as a Standard with reference to BS 6468:2008 or JIS-B-7518:1993
12. Digital Indicator (Linear Displacement)	0.001 to 50 mm 50 to 100 mm	1 μ m 2 μ m	Calibrate using steel gauge block as standard

Signatory:

1. Murali a/I Subramaniam

Schedule

Issue date: 6 December 2017
Valid until: 17 September 2020



MS ISO/IEC 17025

NO: SAMM 176

Page: 20 of 27

SCOPE OF CALIBRATION: DIMENSIONAL

SITE: CATEGORY I

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
Profile Projector / Tool Maker Microscope / Smart Scope (Measuring accuracies of respective X and Y Axis Only)	0.001 mm to 80 mm 80 mm to 300 mm	5 μ m 7 μ m	Calibrate using Glass Scale as a Standard according to JIS B 7153:1995, Performance No. 9

Signatory:

1. **Murali a/l Subramaniam**

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Schedule

Issue date: 6 December 2017
Valid until: 17 September 2020



MS ISO/IEC 17025

NO: SAMM 176

Page: 21 of 27

SCOPE OF CALIBRATION: TEMPERATURE

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
1. Liquid In Glass Thermometer (Total Immersion)	-30 °C to 250 °C	0.2 °C	Comparison Method Using SPRT Module + PT100
2. Digital Thermometer With Probe	-30 °C to 250 °C	0.2 °C	Comparison Method Using SPRT Module + PT100
3. Mechanical Thermometer	-30 °C to 100 °C 100 °C to 250 °C	0.4 °C 0.7 °C	Comparison Method Using SPRT Module + PT100
4. Temperature Indicating Instruments	<u>Type-K</u> -100 °C to 1300 °C <u>Type-J</u> -100 °C to 1200 °C <u>Type-T</u> -100 °C to 400 °C <u>Type-E</u> -100 °C to 1000 °C <u>Type-R</u> 0 °C to 1700 °C <u>Type-S</u> 0 °C to 1700 °C <u>PT100</u> -100 °C to 800 °C	0.6 °C 0.5 °C 0.7 °C 0.6 °C 1.6 °C 1.5 °C 0.6 °C	Electrical Simulation Using Documenting Process Calibrator based on EA-10/11 and ITS 90 Tables

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Schedule

Issue date: 6 December 2017
Valid until: 17 September 2020



MS ISO/IEC 17025

NO: SAMM 176

Page: 22 of 27

SCOPE OF CALIBRATION: TEMPERATURE

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
5. Temperature Block Calibrator	-40 °C to 250 °C 250 °C to 600 °C	0.2 °C 1.1 °C	Using SPRT Module with PT 100 and Digital Multi Thermometer with PRT Based on EA- 10/13
6. Thermo-Hygrometer / Thermo-Hygrograph	30 %rh to 90 %rh 10 °C to 50 °C	4 %rh 1.0 °C	Comparison method using Std. Temperature and Humidity Meter based on BS 1339- 3:2004

Signatory:

1. Zaidi Bin Borham

NO: SAMM 176

Page: 23 of 27

SCOPE OF CALIBRATION: TEMPERATURE

SITE CALIBRATION: CATEGORY I

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
1. Temperature Indicating Instruments	<u>Type-K</u> -100 °C to 1300 °C <u>Type-J</u> -100 °C to 1200 °C <u>Type-T</u> -100 °C to 400 °C <u>Type-E</u> -100 °C to 1000 °C <u>Type-R</u> 0 °C to 1700 °C <u>Type-S</u> 0 °C to 1700 °C <u>PT100</u> -100 °C to 800 °C	0.6 °C 0.6 °C 0.7 °C 0.6 °C 1.6 °C 1.5 °C 0.7 °C	Electrical Simulation Using Documenting Process Calibrator based on EA-10/11 and ITS 90 Tables
2. Temperature Controlled Enclosure	-20 °C to 250 °C	1.2 °C	Using Temperature Recorder and Thermocouple Wires based on AS 2853
3. Temperature Sensor with Indicator	30 °C to 250 °C	0.8 °C	Calibration by comparison method using: 1. Digital Multi Thermometer with PRT 2. Dry Block Calibrator

Signatory:

1. Zaidi Bin Borham

NO: SAMM 176

Page: 24 of 27

SCOPE OF CALIBRATION: MASS

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
Standard Weights	1 mg 2 mg 5 mg 10 mg 20 mg 50 mg 100 mg 200 mg 500 mg 1 g 2 g 5 g 10 g 20 g 50 g 100 g 200 g 500 g	0.009 mg 0.009 mg 0.019 mg 0.011 mg 0.012 mg 0.015 mg 0.018 mg 0.023 mg 0.027 mg 0.031 mg 0.038 mg 0.049 mg 0.061 mg 0.082 mg 0.14 mg 0.20 mg 0.32 mg 0.77 mg	Comparison Method using ABBA weighing scheme Using E2 Standard Weights by ABBA comparison weighing scheme
Standard Weights	1 kg 2 kg 5 kg 10 kg 20 kg 25 kg	0.08 g 0.11 g 0.14 g 0.17 g 0.32 g 0.40 g	Using Standard Weights F1, F2 ABBA Method

Signatory:

1. Murali a/l Subramaniam

Schedule

Issue date: 6 December 2017
Valid until: 17 September 2020



MS ISO/IEC 17025

NO: SAMM 176

Page: 25 of 27

SCOPE OF CALIBRATION: MASS

SITE CALIBRATION: CATEGORY I

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
1. Analytical Balance	Up to 200 g	0.2 mg	Using Std. Weight E2 as a Standard with reference to OIML R 76-I Edition 2006(E)
2. Electronic Balance	Up to 500 g Up to 1 kg Up to 10 kg Up to 20 kg Up to 100 kg Up to 200 kg Up to 500 kg Up to 1000 kg Up to 2000 kg	1.5 mg 6 mg 61 mg 100 mg 20 g 36 g 171 g 213 g 460 g	Using Standard Weight E2, F1, F2, M2 as a Standard with reference to OIML R 76-I Edition 2006(E)

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Schedule

Issue date: 6 December 2017
Valid until: 17 September 2020



MS ISO/IEC 17025

NO: SAMM 176

Page: 26 of 27

SCOPE OF CALIBRATION: FORCE

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
Digital Force Gauges / Push Pull Gauges / Tension Gauges	1 mgf to 10 kgf 10 kgf to 50 kgf 50 kgf to 100 kgf	0.6 gf 10 gf 61 gf	Using Std. Weight as a Standard

Signatory:

1. Murali a/l Subramaniam

SCOPE OF CALIBRATION: FORCE

SITE CALIBRATION: CATEGORY I

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
Universal Testing Machine (Compression Mode)	150 kgf to 1000 kgf 1001 kgf to 5000 kgf 5001 kgf to 10000 kgf	0.2 kgf 3.2 kgf 2.6 kgf	Using Std. Load Cell * Calibration Loop as a Standard with reference to ISO 7500-1:2004

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NO: SAMM 176

Page: 27 of 27

SCOPE OF CALIBRATION: PRESSURE

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
Pressure Indicating Instruments (hydraulic medium)	0 psi to 800 psi	0.03 % of Reading	Using Dead Weight Tester / Pressure Comparator as a Standard
	800 psi to 16000 psi	0.03 % of Reading	

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1. Murali a/l Subramaniam

SCOPE OF CALIBRATION: PRESSURE**SITE CALIBRATION: CATEGORY I**

Instrument Calibrated/ Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty($\pm$)*	Remarks
Pressure Indicating Instruments (hydraulic medium)	0 psi to 800 psi	0.05 % of Reading + 0.06 psi	Using Pressure Comparator as a Standard
	800 psi to 16000 psi	0.06 % of Reading + 0.03 psi	

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1. Murali a/l Subramaniam